

<p style="text-align: right;">O I P E MAR 27 2006 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)</p>				ATTY. DOCKET NO. 854163.414	APPLICATION NO. 10/824,631		
				APPLICANT Fabio Pellizzer			
				FILING DATE April 14, 2004	GROUP ART UNIT 2815		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,789,277	08/04/98	Zahorik et al.	438	95	
	AB	5,814,527	09/29/98	Wolstenholme et al.	438	5	
	AC	5,952,671	09/14/99	Reinberg et al.	257	3	
	AD	5,970,336	10/19/99	Wolstenholme et al.	438	238	
	AE	6,031,287	02/29/00	Harshfield	257	734	
	AF	6,238,946	05/29/01	Ziegler	438	50	
	AG	6,313,604	11/06/01	Maimon et al.	438	95	
	AH	6,541,333	04/01/03	Shukuri et al.	438	243	
	AI	6,613,604	09/02/03	Maimon et al.	438	95	
	AJ	6,617,192	09/09/03	Lowrey et al.	438	95	
	AK	6,750,079	06/15/04	Lowrey et al.	438	95	
	AL	6,759,267	07/06/04	Chen	438	95	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AM	WO 00/57498	09/28/00	WIPO	YES	NO	
	AN						
	AO						
	AP						
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ		Palun, L. et al., "Fabrication of Single Electron Devices by Hybrid (E-Beam/DUV) Lithography," Microelectronic Engineering 53, pp. 167-170, 2000.				
	AR						
EXAMINER <i>JOSEPH HAN YEN</i>			DATE CONSIDERED <i>4/3/06</i>				
<p>* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).</p>							

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	BA	6,777,705	08/17/04	Reinberg et al.	257	2	
	BB	6,943,365	09/13/05	Lowrey et al.	257	3	
	BC	6,972,430	12/06/05	Casagnade et al.	257	4	
	BD	6,969,866	11/29/05	Lowrey et al.	257	3	
	BE	2002/0070401	06/13/02	Takeuchi et al.	257	296	
	BF	2003/0075778	04/24/03	Klersy	257	536	
	BG	2003/0219924	11/27/03	Bez et al.	438	102	
	BH	2004/0113181	01/22/04	Klebanoff et al.	134	2	
	BI	2004/0166604	08/26/04	Ha et al.	438	102	
	BJ	2004/0245603	12/09/04	Lowrey et al.	257	536	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION
					YES NO
	BK				
	BL				
	BM				
	BN				
	BO				

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	BP		
	BQ		
	BR		

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<i>JOSEPH HAUEN</i>	<i>4/3/06</i>

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